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Neeb

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(54) **SYSTEM AND METHOD FOR TESTING SEMICONDUCTOR DEVICES**

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(58) Field of Search **324/754-758, 324/761-762, 765, 158.1**

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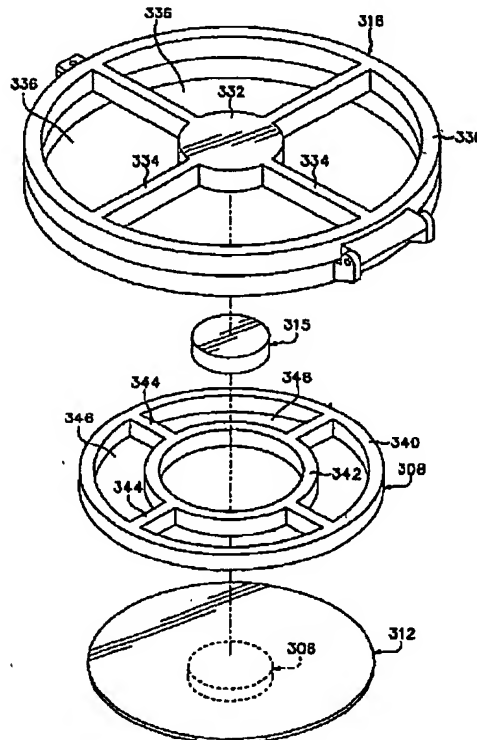
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(57) **ABSTRACT**

The invention(s) relates to semiconductor test system and method that isolates and counteracts forces that bend test equipment resulting in improved manufacturing yield and throughput. The system includes a force retainer fixedly mounted on a material handler and a force locator positioned between the force retainer and a circuit board. Together, the force retainer and locator prevent the circuit board from bending. Other embodiments are illustrated and described.

18 Claims, 4 Drawing Sheets



EXH A
PAGE 1 OF 1